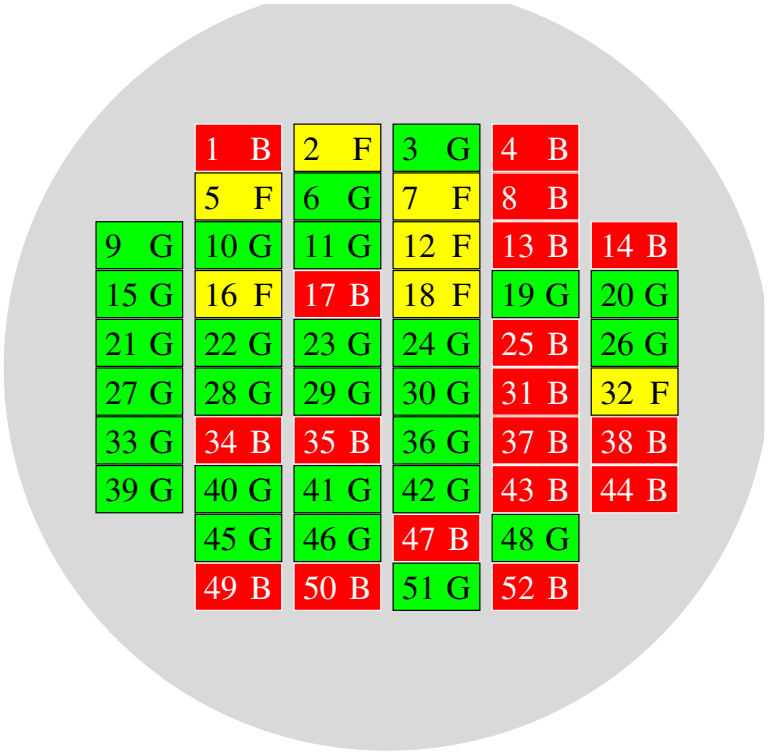
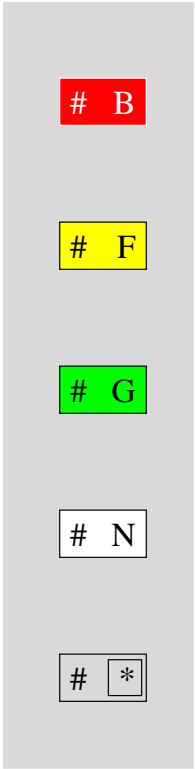
Die quality map for wafer 36 s/n: 21316-03-23

Date: 11/01/98